DATA SHEET



MOS FIELD EFFECT TRANSISTOR μ PA2450C

N-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The $\mu\,\mathrm{PA2450C}$ is a switching device, which can be driven directly by a 2.5 V power source.

The μ PA2450C features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- 2.5 V drive available
- · Low on-state resistance

 $R_{DS(on)1} = 17.5 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 4.5 \text{ V, I}_D = 4.0 \text{ A)}$

 $R_{DS(on)2} = 18.5 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 4.0 \text{ V, Ip} = 4.0 \text{ A)}$

 $R_{DS(on)3} = 22.0 \text{ m}\Omega \text{ MAX.}$ (Vgs = 3.1 V, ID = 4.0 A)

 $R_{DS(on)4} = 27.5 \text{ m}\Omega \text{ MAX.} \text{ (Vgs = 2.5 V, ID = 4.0 A)}$

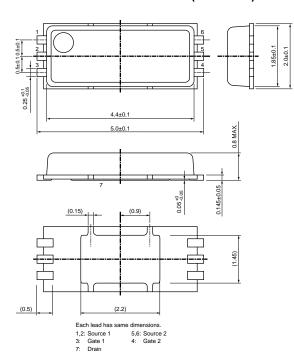
· Built-in G-S protection diode against ESD

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

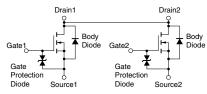
VDSS	20.0	V
Vgss	±12.0	V
ID(DC)	±8.6	Α
D(pulse)	±70.0	Α
P _{T1}	2.5	W
P _{T2}	0.7	W
Tch	150	°C
Tstg	-55 to +150	°C
	VGSS ID(DC) ID(pulse) PT1 PT2 Tch	VGSS ±12.0 ID(DC) ±8.6 ID(pulse) ±70.0 PT1 2.5 PT2 0.7 Tch 150

- Notes 1. Mounted on ceramic board of 50 cm² x 1.1 mmt
 - **2.** PW \leq 10 μ s, Duty Cycle \leq 1%
 - 3. Mounted on FR-4 board of 50 cm² x 1.1 mmt

PACKAGE DRAWING (Unit: mm)



EQUIVALENT CIRCUIT



ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE
μ PA2450CTL-E1-A Note		Reel	
μ PA2450CTL-E2-A Note	Sn-Bi	3000 p/reel	6PIN HWSON (4521)

Note Pb-free (This product does not contain Pb in the external electrode and other parts.)

Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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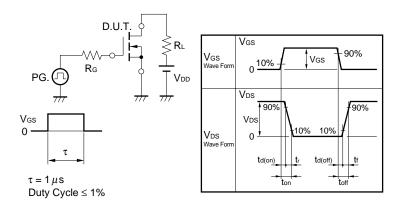
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ELECTRICAL CHARACTERISTICS (TA = 25°C)

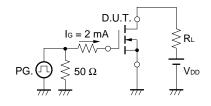
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 20.0 V, V _{GS} = 0 V			1.0	μΑ
Gate Leakage Current	Igss	V _{GS} = ±12.0 V, V _{DS} = 0 V			±10.0	μΑ
Gate to Source Cut-off Voltage	V _{GS(off)}	V _{DS} = 10.0 V, I _D = 1.0 mA	0.50		1.50	V
Forward Transfer Admittance Note	yfs	V _{DS} = 10.0 V, I _D = 4.0 A	3.5			S
Drain to Source On-state Resistance Note	RDS(on)1	V _{GS} = 4.5 V, I _D = 4.0 A	11.0	12.5	17.5	mΩ
	RDS(on)2	V _{GS} = 4.0 V, I _D = 4.0 A	11.5	13.0	18.5	mΩ
	RDS(on)3	V _{GS} = 3.1 V, I _D = 4.0 A	12.0	14.5	22.0	mΩ
	RDS(on)4	V _{GS} = 2.5 V, I _D = 4.0 A	15.3	18.0	27.5	mΩ
Input Capacitance	Ciss	V _{DS} = 10.0 V,		564		pF
Output Capacitance	Coss	V _{GS} = 0 V,		102		pF
Reverse Transfer Capacitance	Crss	f = 1.0 MHz		64		pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = 10.0 V,		26.5		ns
Rise Time	tr	I _D = 4.0 A,		81		ns
Turn-off Delay Time	t _{d(off)}	V _{GS} = 4.0 V,		136		ns
Fall Time	tr	$R_G = 6 \Omega$		97		ns
Total Gate Charge	QG	V _{DD} = 16.0 V,		6.0		nC
Gate to Source Charge	QGS	V _{GS} = 4.0 V,		1.3		nC
Gate to Drain Charge	Q _{GD}	I _D = 8.6 A		2.3		nC
Body Diode Forward Voltage Note	V _{F(S-D)}	I _F = 8.6 A, V _{GS} = 0 V		0.82		V

Note Pulsed: PW \leq 350 μ s, Duty Cycle \leq 2%

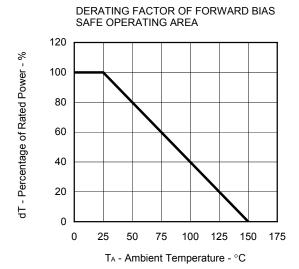
TEST CIRCUIT 1 SWITCHING TIME



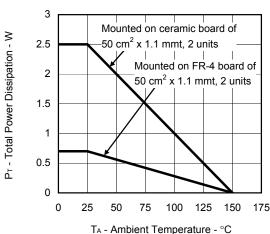
TEST CIRCUIT 2 GATE CHARGE



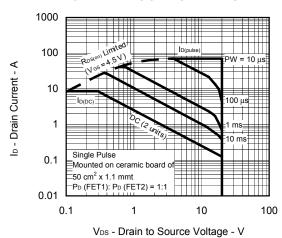
ELECTRICAL CHARACTERISTICS (TA = 25°C)



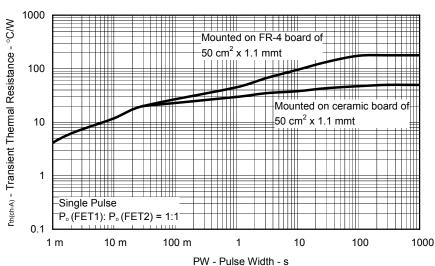
TOTAL POWER DISSIPATION vs. AMBIENT TEMPERATURE



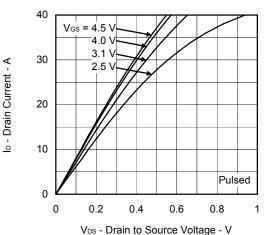
FORWARD BIAS SAFE OPERATING AREA



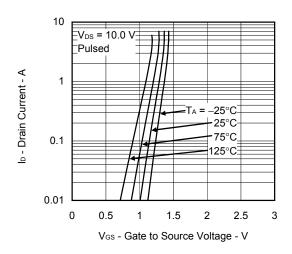




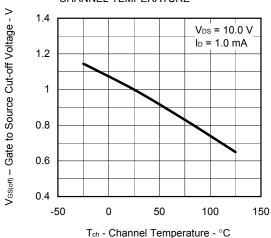




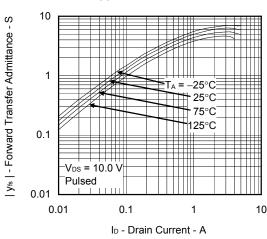
FORWARD TRANSFER CHARACTERISTICS



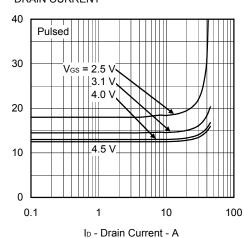
GATE TO SOURE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



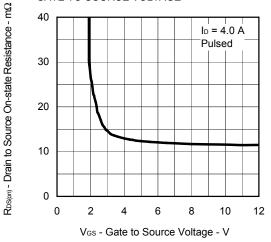
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

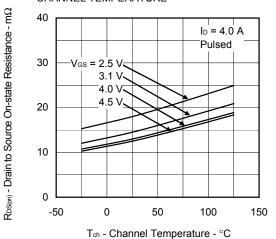


DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

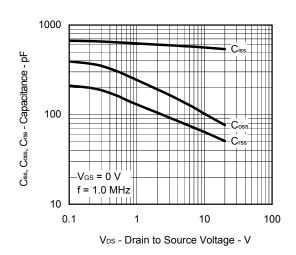


 $\mathsf{R}_{\mathsf{DS}(\varpi)}$ - Drain to Source On-state Resistance - $m\Omega$

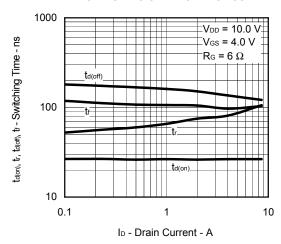
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



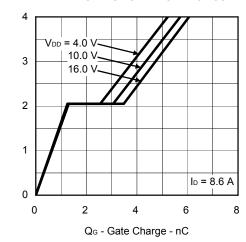
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



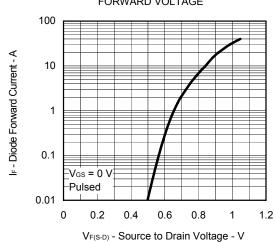
SWITCHING CHARACTERISTICS



DYNAMIC INPUT CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE



5

Ves - Gate to Drain Voltage - V

NEC μ PA2450C

<Notes for using this device safely>

When you use this device, in order to prevent a customer's hazard and damage, use it with understanding the following contents. If used exceeding recommended conditions, there is a possibility of causing failure of the device and characteristic degradation.

- 1. When you mount the device on a substrate, carry out within our recommended soldering conditions of infrared reflow. If mounted exceeding the conditions, the characteristic of a device may be degraded and it may result in failure.
- 2. When you wash the device mounted the substrate, carry out within our recommended conditions. If washed exceeding the conditions, the characteristic of a device may be degraded and it may result in failure.
- 3. When you use ultrasonic wave to substrate after the device mounting, prevent from touching a resonance generator directly. If it touches, the characteristic of a device may be degraded and it may result in failure.
- 4. Please refer to **Figure 1** as an example of the land pattern. Optimize the land pattern in consideration of density, appearance of solder fillets, common difference, etc in an actual design.

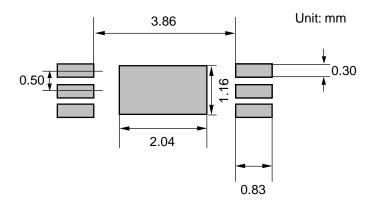


Figure 1. Example of the land pattern

5. This device is very thin device and should be handled with caution for mechanical stress. The rate of distortion applied to the device should become below 2000 $\mu\epsilon$. Note1 If the rate of distortion exceeds 2000 $\mu\epsilon$, the characteristic of a device may be degraded and it may result in failure.

Figure 2. Direction of substrate and stress

The substrate that mounted the device is on a stand with a support width of 24 mm.

The device is turned downward. The stress is applied from a top.

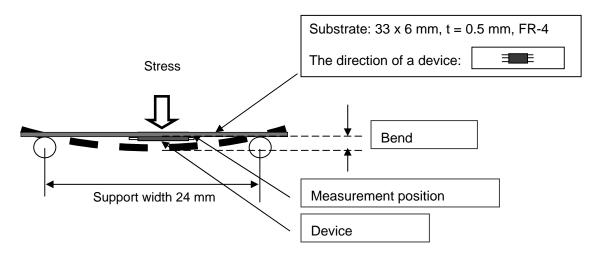
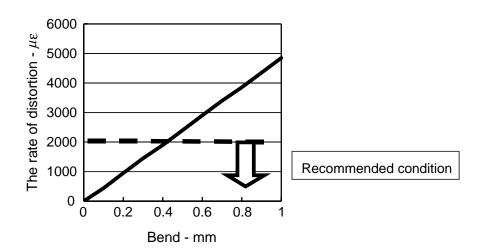


Figure 3. Example of the bend and the rate of distortion $^{\mathrm{Note2}}$



Note 1. Definition of rate of distortion(written as ε in this document)

- $\varepsilon = (I I_0)/I_0$
- lo: Distance for two arbitrary points before receiving stress.
- I: Distance above-mentioned when receiving stress.
- **2.** The relation of the distortion and the bend changes with several conditions, such as a size of substrate and so on.

μ PA2450C

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